

# Search Notes



Application/Control No.

10/691,133

Examiner

Emmanuel Bayard

Applicant(s)/Patent under Reexamination

CHEN ET AL.

Art Unit

2611

## SEARCHED

Class	Subclass	Date	Examiner
375	229	6/16/06	EB
↑	231	↑	↑
	232		
	233		
	234		
↓	350	↓	↓
375	295	6/16/06	EB

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
α ASI	6/16/06	EB